

| | | | |
|-----------------------------------|---------------------------------------|---|-------------|
| Notice of References Cited | Application/Control No. 10/037,431 | Applicant(s)/Patent Under Reexamination TUOMIKOSKI ET AL. | |
| | Examiner Dinh Q Nguyen | Art Unit 3752 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------------|----------------|
| | A | US-3,000,022 | 09-1961 | Cathey et al. | 441/65 |
| | B | US-3,945,568 | 03-1976 | Bychowski, William E. | 239/57 |
| | C | US-4,779,794 | 10-1988 | Moore, Gail S. | 232/1B |
| | D | US-4,944,455 | 07-1990 | Haust et al. | 239/59 |
| | E | US-6,237,788 | 05-2001 | Shuen, Shun Tian | 215/12.1 |
| | F | US-4,159,631 | 07-1979 | Lee, Ki S. | 63/1.15 |
| | G | US-6,010,540 | 01-2000 | Telesca et al. | 8/142 |
| | H | US-6,543,365 | 04-2003 | Vasel et al. | 102/502 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.